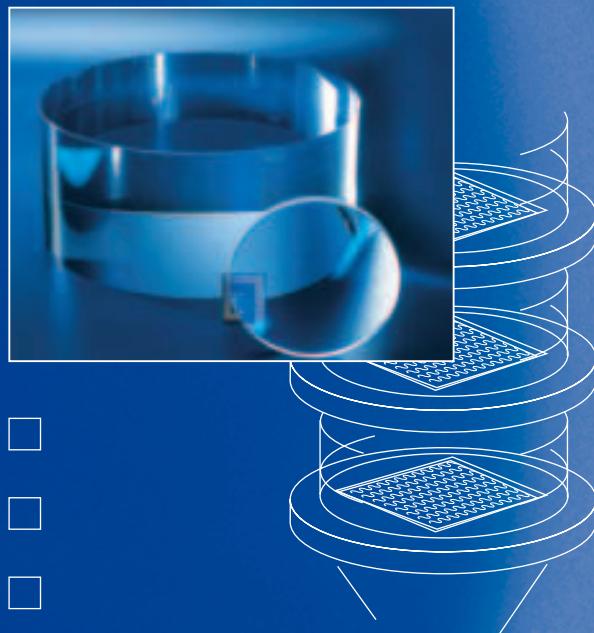


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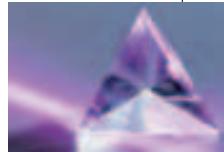
# Calcium Fluoride

VUV/DUV/UV, VIS & IR applications



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SCHOTT  
lithotec



# SCHOTT Lithotec Calcium Fluoride

Calcium fluoride single crystals, grown from high purity raw materials, are required for illumination and projection optics in 248 and 193 nm **microlithography technologies**. SCHOTT Lithotec's expertise allows fabrication of CaF<sub>2</sub> blanks in diameters up to 350 mm and with a thickness exceeding 100 mm and highest transmission down to 157 nm.

## Key quality features are:

- Excellent UV transmittance
- High laser durability
- Low stress birefringence
- High refractive index homogeneity

The very high laser durability of CaF<sub>2</sub> makes it the first choice material for litho **excimer laser optics, beam deliveries**, and for all excimer wavelengths in a wide range of other applications.

Synthetic calcium fluoride crystals complete the application range of **optical materials** from VUV to IR with a very good transmission ranging from 130 nm to 9 µm. Advantages in optical performance can be achieved with calcium fluoride in chromatically corrected optical systems in astronomy, photography, HDTV zoom lenses, as well as in microscopy. Further applications are sensors (especially in IR spectrum), spectrometers and medical lasers.

SCHOTT Lithotec offers CaF<sub>2</sub> components and blanks with different crystal orientations (<111>, <100>, random or others on request) along with different surface qualities (raw, cut, ground or polished), depending on the individual requirements.



# Fields of Application



## IC Litho: Manufacturing Tools

Typical Dimensions:		up to 350 mm diameter, 80 mm thickness		
Wavelength:	248 nm	193 nm	157 nm	
Internal Transmittance per 10 mm sample thickness [%]	> 99.8	> 99.7	> 99.4	
Refractive Index Homogeneity PV @ 633 nm [ppm]	1 ... 15 (depending on diameter)			
Stress Birefringence PV @ 633 nm [nm/cm] *	1 ... 20			
Bubbles, Inclusions (ISO 10110-3)	1/1 x 0.063 (typical)			

## IC Litho: Excimer Laser & Beam Delivery Systems

Typical dimensions: disks - up to 100 mm diameter / 30 mm thickness; prisms - up to 100 mm edge length	
Characteristic Parameters:	See table above: Litho Manufacturing Tools
<b>Laser Durability:</b> SCHOTT Lithotec offers material with a laser durability up to highest requirements which is categorized by an internal classification method. In addition to volume characteristics, laser durability is also dependent on surface quality (with increasing laser energies) and on the laser operating conditions.	
Laser Durability Classification:	LD-A: Superior      LD-C: Advanced LD-B: High      LD-D: Standard
A qualified long-term laser durability is provided by each of these classes adapted to the individual application requirements. Please define application wavelength, energy density, repetition rate, pulse length and pulse number.	
Laser Damage Threshold @ 193 nm	~7 J/cm <sup>2</sup> (effects: surface defects, ablation)

## Non-Litho: Laser & Imaging Optics

Typical Dimensions: Max. dimensions:		100 mm diameter, 30 mm thickness up to 350 mm diameter, 80 mm thickness
Available Grades	UV grade / 193 - 400 nm VIS grade / 400 - 780 nm IR grade / 0.78 - 6.00 µm	
Internal Transmittance per 10 mm sample thickness [%]	> 99.0	
Refractive Index Homogeneity PV @ 633 nm [ppm]	3 ... 20	
Stress Birefringence PV @ 633 nm [nm/cm] *	1 ... 50	
Bubbles, Inclusions (ISO 10110-3)	1/1 x 0.10 (typical)	

\* ) For single crystalline material; smallest value referring to <111> orientation.  
Polycrystalline material is also available.



For other specifications and individual requirements regarding dimensions, material and surface quality please contact our sales department.  
See also: Request for Quotation (advice for download on page No. 7)

# Properties of Calcium Fluoride

## Optical Properties

Refractive Indices n(N <sub>2</sub> ) (at 22°C, nitrogen atmosphere, 1013 hPa)		
	λ <sub>vac</sub> [nm]	n*
n <sub>2325</sub>	2325.59	1.42212
n <sub>1970</sub>	1970.56	1.42401
n <sub>1530</sub>	1530.00	1.42612
n <sub>1060</sub>	1060.00	1.42851
n <sub>t</sub>	1014.25	1.42879
n <sub>s</sub>	852.35	1.43002
n <sub>r</sub>	706.71	1.43166
n <sub>C</sub>	656.45	1.43245
n <sub>C'</sub>	644.03	1.43267
n <sub>He-Ne</sub>	632.98	1.43288
n <sub>D</sub>	589.46	1.43380
n <sub>d</sub>	587.73	1.43384
n <sub>e</sub>	546.23	1.43493
n <sub>F</sub>	486.27	1.43701
n <sub>F'</sub>	480.13	1.43726
n <sub>g</sub>	435.96	1.43946
n <sub>h</sub>	404.77	1.44148
n <sub>i</sub>	365.12	1.44488
n <sub>334</sub>	334.24	1.44848
n <sub>312</sub>	312.66	1.45173
n <sub>296</sub>	296.82	1.45463
n <sub>280</sub>	280.43	1.45824
n <sub>248</sub>	248.35	1.46791
n <sub>194</sub>	194.23	1.50060
n <sub>193</sub>	193.37	1.50143
n <sub>184</sub>	184.95	1.51055
n <sub>157**</sub>	157.63	1.55927

\* ) Tolerances of refractive indices: ±2·10<sup>-5</sup>  
 \*\* ) Measurement at NIST on 08-01-00  
 All refractive indices are interpolated from values measured under dry nitrogen;  
 λ<sub>vac</sub> = vacuum wavelength.

Relative Partial Dispersion	
P <sub>s,t</sub>	0.2698
P <sub>C,s</sub>	0.5333
P <sub>d,C</sub>	0.3046
P <sub>e,d</sub>	0.2388
P <sub>g,F</sub>	0.5389
P <sub>i,h</sub>	0.7462

Deviation of Relative Partial Dispersions from "Normal Line"	
ΔP <sub>C,t</sub>	-0.1935
ΔP <sub>C,s</sub>	-0.0915
ΔP <sub>F,e</sub>	0.0183
ΔP <sub>g,F</sub>	0.0552
ΔP <sub>i,g</sub>	0.2636



$n_d = 1.43384$	$v_d = 95.23$	$n_f - n_c = 0.00456$
$n_e = 1.43493$	$v_e = 94.69$	$n_{f'} - n_{c'} = 0.00459$

Constants of formula for dn <sub>abs</sub> /dT in vacuum	
D <sub>0</sub>	-3.18 · 10 <sup>-5</sup>
D <sub>1</sub>	-2.31 · 10 <sup>-8</sup>
D <sub>2</sub>	4.13 · 10 <sup>-11</sup>
E <sub>0</sub>	3.35 · 10 <sup>-7</sup>
E <sub>1</sub>	1.91 · 10 <sup>-10</sup>
λ <sub>TK</sub> [μm]	0.192

valid for 365 nm < λ < 1014 nm and for -100°C ≤ T ≤ +140°C

Temperature coefficients of the refractive index								
wavelength [nm]	Δn <sub>rel</sub> /ΔT [10 <sup>-6</sup> /K]*	Δn <sub>abs</sub> /ΔT [10 <sup>-6</sup> /K]**	1060.0	546.23	365.12	1060.0	546.23	365.12
-40/-20 [°C]	-8.6	-8.3	-7.7	-10.5	-10.3	-9.7		
+20/+40 [°C]	-10.4	-10.1	-9.5	-11.6	-11.4	-10.8		
+60/+80 [°C]	-11.2	-11.0	-10.3	-12.2	-12.0	-11.3		

\*) relative to nitrogen

\*\*) relative to vacuum

Constants of Sellmeier Dispersion Formula for λ <sub>vac</sub> and n(N <sub>2</sub> )	
B <sub>1</sub>	6.188140 · 10 <sup>-1</sup>
B <sub>2</sub>	4.198937 · 10 <sup>-1</sup>
B <sub>3</sub>	3.426299
C <sub>1</sub>	2.759866 · 10 <sup>-3</sup>
C <sub>2</sub>	1.061251 · 10 <sup>-2</sup>
C <sub>3</sub>	1.068123 · 10 <sup>3</sup>

Sellmeier Dispersion Formula (according to SCHOTT Technical Information TIE29 Literature link: 9)	
n <sup>2</sup> -1 = B <sub>1</sub> λ <sup>2</sup> /(λ <sup>2</sup> -C <sub>1</sub> ) + B <sub>2</sub> λ <sup>2</sup> /(λ <sup>2</sup> -C <sub>2</sub> ) + B <sub>3</sub> λ <sup>2</sup> /(λ <sup>2</sup> -C <sub>3</sub> ) with λ in μm	

valid for 184 nm < λ < 2326 nm (22°C; 1013 hPa); n = n(N<sub>2</sub>); λ = λ<sub>vac</sub>

## Additional Properties

Chemical/Electrical Properties		Chemical Behavior of Polished Surfaces	
Solubility in water [g/l] 20°C	0.016	Climatic Resistance Class (ISO/WD 13384)	CR 1
Crystal type	single crystal, synthetic	Acid Resistance Class (ISO 8424)	SR 4.5
Crystal structure	cubic; CaF <sub>2</sub> type structure	Alkali Resistance Class (ISO 10629)	AR 2.3
Cleavage planes	(111)	Phosphate Resistance Class (ISO 9689)	PR 1.3
Lattice constant [nm]	0.546342	Stain Resistance Class	FR 0
Thermal Properties		Mechanical Properties	
Melting point [°C]	1420	Young's Modulus (25°C) [GPa]	75.8
Mean specific heat C <sub>p</sub> (20°-100°C) [J/(kg · K)]	854	Shear Modulus (25°C) [GPa]	33.77
Heat conductivity λ (20°C) [W/(m · K)]	9.71	Compressive Strength [GPa]	83.8
Linear thermal Expansion coefficent α (20°C ; 300°C) [10 <sup>-6</sup> /K]	21.28	Poisson's Ratio μ	0.26
α (-30°C ; 70°C) [10 <sup>-6</sup> /K]	18.41	Knoop Hardness (ISO 9385) HK	158.3
		Mohs Hardness	4.0
		Density ρ [g/cm <sup>3</sup> ]	3.18
		Grindability (ISO 12844) HG	6
Stress-Optical Coefficients (q <sub>11</sub> -q <sub>12</sub> ) and q <sub>44</sub> measured at NIST**			
λ (nm)	CaF <sub>2</sub>		
	(q <sub>11</sub> -q <sub>12</sub> ) (10 <sup>-12</sup> Pa <sup>-1</sup> )	q <sub>44</sub> (10 <sup>-12</sup> Pa <sup>-1</sup> )	
637.8*	-1.46 ± 0.01	0.71 ± 0.01	
546.4	-1.53 ± 0.02	0.75 ± 0.01	
436.0	-1.55 ± 0.02	0.74 ± 0.01	
365.1	-1.57 ± 0.02	0.74 ± 0.01	
253.7	-1.66 ± 0.02	0.73 ± 0.01	
193.1	-1.77 ± 0.02	0.66 ± 0.01	
156.1	-1.91 ± 0.05	0.45 ± 0.01	
157.63 (linear int.)	-1.90	0.46	

\*) all values related to (111) direction

\*\*) Lit. 2

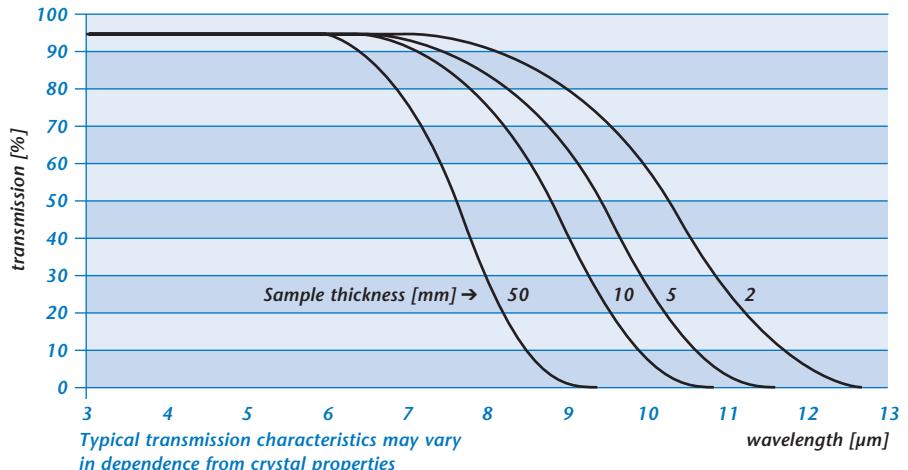
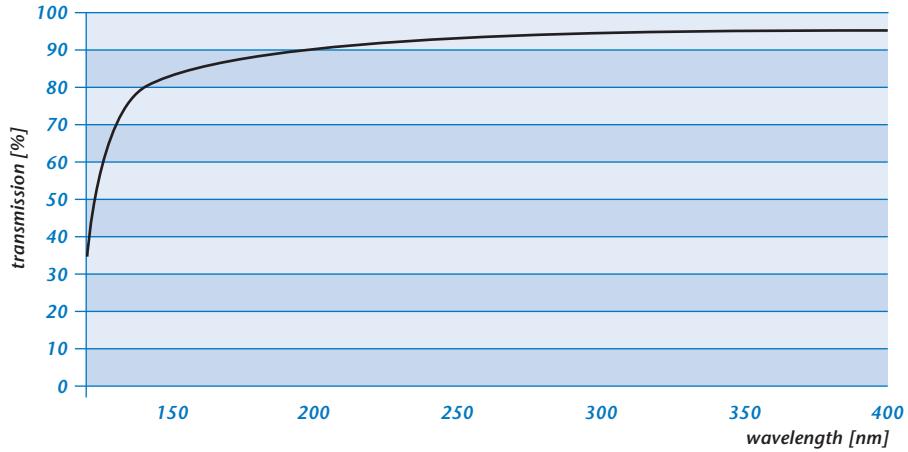
For further technical information please see Lit. 1, 9, 10





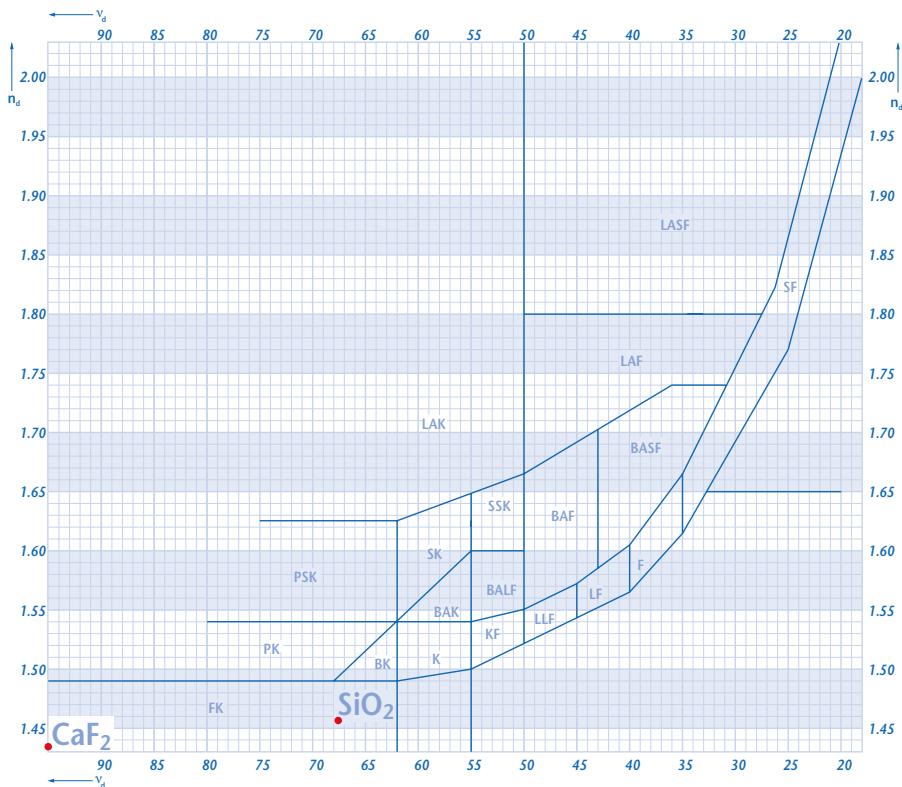
# Spectral Transmission

The very broad spectral transmission range of calcium fluoride from 130 nm to 9  $\mu\text{m}$  (depending on sample thickness) makes it suitable for various applications in the ultraviolet, visible and infrared spectrum.





# Abbe Diagram



**The following downloads are available at:**

<http://www.schott.com/lithotec>

[http://www.schott.com/optics\\_devices](http://www.schott.com/optics_devices)

- Request for Quotation (RfQ)
- Advice for Material Handling
- Material Safety Data Sheet (MSDS)
- RoHS Statement (Restriction of Hazardous Substances)
- ISO 9001 Certificate
- Optical Glass: Description of Properties
- Technical Data Sheets (ASCII, Zemax Format)
- Abbe Diagram

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6. L. Parthier, G. Grabosch, U. Natura, M. Letz, K. Knapp, "ArF Immersion Lithography – a new challenge for CaF<sub>2</sub> quality", SPIE Microlithography, Santa Clara, 2005
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**SCHOTT Lithotec AG**  
Sales Office  
Otto-Schott-Strasse 13  
07745 Jena  
Germany  
Phone: +49 (0)3641/232-270  
Fax: +49 (0)3641/232-132  
E-mail: [lithotec@schott.com](mailto:lithotec@schott.com)  
[www.schott.com/lithotec](http://www.schott.com/lithotec)